

<b>Notice of References Cited</b>	Application/Control No. 10/724,374	Applicant(s)/Patent Under Reexamination BAE ET AL	
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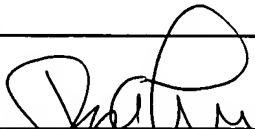
#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,190,700 A	03-1993	Watanabe et al.	252/609
	B	US-5,519,077 A	05-1996	Drewes et al.	524/114
	C	US-4,464,495	08-1984	Brown, Randall J.	524/87
	D	US-5,004,776	04-1991	Tadenuma et al.	524/377
	E	US-5,744,525 A	04-1998	Harvey et al.	524/84
	F	US-6,825,256 B2	11-2004	Bae et al.	524/297
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 61-9451 A	01-1986	Japan	Akimine et al.	C08L 27/04
	O	JP 4-268355 A	09-1992	Japan	Kano et al.	C08L 27/06
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	JP 61-9451 (abstract in English)
	V	JP 4-268355 (abstract in English)
	W	
	X	

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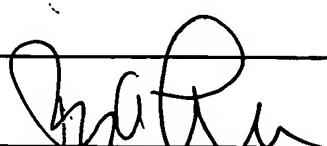
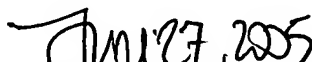
**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,245,846 B1	06-2001	Daniels et al.	524/409
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
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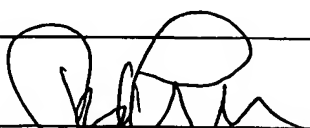
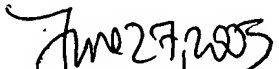
**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,084,013 A	07-2000	Wehner, Wolfgang	524/100
	B	US-4,659,764	04-1987	Isao et al.	524/399
	C	US-4,464,495	08-1984	Brown, Randall J.	524/87
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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